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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/654,438	09/04/2003	Toshiyuki Tokura	2611-0196P	5153

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EXAMINER
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DIACOU, ARI M

ART UNIT	PAPER NUMBER
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3663

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Please find below and/or attached an Office communication concerning this application or proceeding.

## POST-ALLOWANCE COMMUNICATION

### *Information Disclosure Statement*

1. The IDS filed on 6-17-2005 and again on 1-25-2006 has been considered and initialed. The references therein have not been found to read on the claimed invention.

### **Conclusion**

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Ari M. Diacou whose telephone number is (571) 272-5591. The examiner can normally be reached on Monday - Friday, 8:30 am - 5:00 pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Jack Keith can be reached on (571) 272-6878. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

AMD 2/16/2006

  
JACK KEITH  
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